

<b>Notice of References Cited</b>	Application/Control No. 10/623,286		Applicant(s)/Patent Under Reexamination FINN ET AL.	
	Examiner DEVONA E. FAULK		Art Unit 2615	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,442,712	08-1995	Kawamura et al.	381/83
*	B	US-2004/0158460	08-2004	Finn et al.	704/205
*	C	US-6,252,969	06-2001	Ando, Shigeo	381/103
*	D	US-6,125,187	09-2000	Hanajima et al.	381/83
*	E	US-6,674,865	01-2004	Venkatesh et al.	381/107
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.